Search Notes		

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/670,787	HAN ET AL.	
Examiner	Art Unit	
Jason M. Han	2875	

SEARCHED			
Class	Subclass	Date	Examiner
362	29-30	12/16/2005	JMH
362	97	12/16/2005	JMH
362	260	12/16/2005	JMH
349	70	12/16/2005	ЈМН
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INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
Search Update - EAST (US-PGPUB, USPAT, USOCR, EPO, JPO, DERWENT) - See Interference	12/16/2005	JMH	
P.E. Alan Cariaso	12/16/2005	ЈМН	